

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	26	electromagnetic\$4 near2 (field signal) with (defect\$4 fail\$4 fault\$4 malfunction\$4) with (ic integrated adj circuit)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/04 15:57
S2	12040	324/765,750-753,158.1.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/04 15:49
S3	695789	electromagnetic\$4	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/04 15:49
S4	771	S2 and S3	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/04 15:49
S5	512785	(defect\$4 fail\$4 fault\$4 malfunction\$4) and (semiconductor ic integrated adj circuit)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/04 15:57
S6	370	S4 and S5	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/05 04:03
S7	3	10/600919	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/05 04:01

EAST Search History

S8	1030672	(detect\$4 monitor\$4 measur\$4) with (voltage current impedance)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/05 04:03
S9	12040	324/765,750-753,158.1.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/05 04:03
S10	695789	electromagnetic\$4	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/05 04:03
S11	771	S9 and S10	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/05 04:03
S12	512785	(defect\$4 fail\$4 fault\$4 malfunction\$4) and (semiconductor ic integrated adj circuit)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/05 04:03
S13	370	S11 and S12	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/05 04:04
S14	1030672	(detect\$4 monitor\$4 measur\$4) with (voltage current impedance)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/05 16:48

EAST Search History

S15	12040	324/765,750-753,158.1.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/05 16:48
S16	695789	electromagnetic\$4	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/05 17:17
S17	771	S15 and S16	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/05 16:48
S18	512785	(defect\$4 fail\$4 fault\$4 malfunction\$4) and (semiconductor ic integrated adj circuit)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/05 18:01
S19	370	S17 and S18	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/05 16:48
S20	257	S14 and S19	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/05 17:04
S21	215063	(gate nmos fet mosfet cmos) with (activat\$4 detect\$3 trigger\$4)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/05 17:05

EAST Search History

S22	35	S20 and S21	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/05 17:06
S23	2274680	electromagnetic\$4 magnetic\$4	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/05 17:17
S24	35	S22 and S23	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/05 17:19
S25	1433882	potential	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/05 17:19
S26	19	S24 and S25	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/05 17:48
S27	8	("4398343" "5233291" "5371459" "5537054" "5897378" "5982190" "6194907" "6320401").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/11/05 17:25
S28	3	09/866651	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/05 17:51

EAST Search History

S29	13	"5514971"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/05 17:51
S30	4	("4271389" "4278933" "4514680" "5128621").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/11/05 17:55
S31	787	324/603-607.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2007/11/05 17:56
S32	134	S23 and S31	US-PGPUB; USPAT; USOCR	OR	ON	2007/11/05 17:57
S33	14	S21 and S32	US-PGPUB; USPAT; USOCR	OR	ON	2007/11/05 17:59
S34	10300	(radiat\$4 generat\$4 apply\$4 inject\$4) near4 (electromagnetic\$4 magnetic\$4) with (semiconductor ic! integrated adj circuit)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/05 18:01
S35	2616	S18 and S34	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/05 18:02
S36	200	S21 and S35	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/05 18:02